Notice of References Cited Application/Control No. 10/576,850 Examiner John P. Sheehan Applicant(s)/Patent Under Reexamination PARK ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0126609 A1	07-2004	Ueta et al.	428/570
*	В	US-2003/0047706 A1	03-2003	Mitani et al.	252/62.54
*	С	US-2002/0084882 A1	07-2002	Moro, Hideharu	336/233
*	D	US-2002/0014280	02-2002	Moro, Hideharu	148/104
*	Е	US-5,822,636	10-1998	Cho, Sung-Jae	396/420
*	F	US-5,470,399	11-1995	Bae, Kwang W.	148/104
	G	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	>						
	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.